

Automated identification of application-dependent safe faults in automotive systems-on-a-chips

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sonza Reorda, Matteo; Hamdioui, Said; **Jenihhin, Maksim**; Sauer, Christian
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Combining fault analysis technologies for ISO26262 functional safety verification

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Determined-safe faults identification : a step towards ISO26262 hardware compliant designs

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A DFT scheme to improve coverage of hard-to-detect faults in FinFET SRAMs

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Use of formal methods for verification and optimization of fault lists in the scope of ISO26262

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Using STLs for effective in-field test of GPUs

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Verifying cache architecture vulnerabilities using a formal security verification flow

